



# RF Power Field Effect Transistors

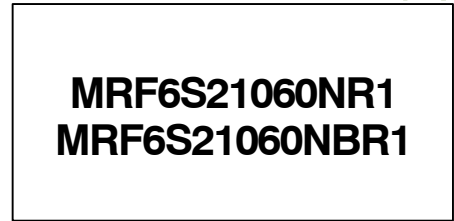
## N-Channel Enhancement-Mode Lateral MOSFETs

Designed for W-CDMA base station applications with frequencies from 2110 to 2170 MHz. Suitable for TDMA, CDMA and multicarrier amplifier applications. To be used in Class AB for PCN-PCS/cellular radio, WLL and TD-SCDMA applications.

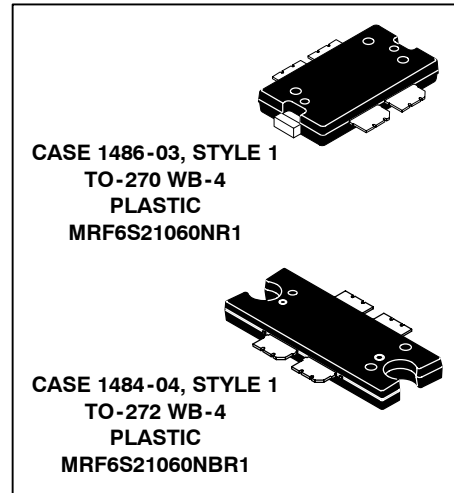
- Typical 2-Carrier W-CDMA Performance:  $V_{DD} = 28$  Volts,  $I_{DQ} = 610$  mA,  $P_{out} = 14$  Watts Avg., Full Frequency Band, Channel Bandwidth = 3.84 MHz, PAR = 8.5 dB @ 0.01% Probability on CCDF.  
Power Gain — 15.5 dB  
Drain Efficiency — 26%  
IM3 @ 10 MHz Offset — -37 dBc in 3.84 MHz Bandwidth  
ACPR @ 5 MHz Offset — -40 dBc in 3.84 MHz Bandwidth
- Capable of Handling 5:1 VSWR, @ 28 Vdc, 2140 MHz, 60 Watts CW Output Power

### Features

- Characterized with Series Equivalent Large-Signal Impedance Parameters
- Internally Matched for Ease of Use
- Qualified Up to a Maximum of 32  $V_{DD}$  Operation
- Integrated ESD Protection
- Designed for Lower Memory Effects and Wide Instantaneous Bandwidth Applications
- 200°C Capable Plastic Package
- N Suffix Indicates Lead-Free Terminations. RoHS Compliant.
- In Tape and Reel. R1 Suffix = 500 Units per 44 mm, 13 inch Reel.



2110-2170 MHz, 14 W AVG., 28 V  
2 x W-CDMA  
LATERAL N-CHANNEL  
RF POWER MOSFETs



**Table 1. Maximum Ratings**

Rating	Symbol	Value	Unit
Drain-Source Voltage	$V_{DSS}$	-0.5, +68	Vdc
Gate-Source Voltage	$V_{GS}$	-0.5, +12	Vdc
Storage Temperature Range	$T_{stg}$	-65 to +150	°C
Operating Junction Temperature	$T_J$	200	°C

**Table 2. Thermal Characteristics**

Characteristic	Symbol	Value (1,2)	Unit
Thermal Resistance, Junction to Case Case Temperature 79°C, 60 W CW Case Temperature 76°C, 14 W CW	$R_{\theta JC}$	0.89 1.04	°C/W

1. MTTF calculator available at <http://www.freescale.com/rf>. Select Tools/Software/Application Software/Calculators to access the MTTF calculators by product.
2. Refer to AN1955, *Thermal Measurement Methodology of RF Power Amplifiers*. Go to <http://www.freescale.com/rf>. Select Documentation/Application Notes - AN1955.

**Table 3. ESD Protection Characteristics**

Test Methodology	Class
Human Body Model (per JESD22-A114)	1B (Minimum)
Machine Model (per EIA/JESD22-A115)	A (Minimum)
Charge Device Model (per JESD22-C101)	III (Minimum)

**Table 4. Moisture Sensitivity Level**

Test Methodology	Rating	Package Peak Temperature	Unit
Per JESD 22-A113, IPC/JEDEC J-STD-020	3	260	°C

**Table 5. Electrical Characteristics** ( $T_C = 25^\circ\text{C}$  unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
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**Off Characteristics**

Zero Gate Voltage Drain Leakage Current ( $V_{DS} = 68\text{ Vdc}$ , $V_{GS} = 0\text{ Vdc}$ )	$I_{DSS}$	—	—	10	$\mu\text{Adc}$
Zero Gate Voltage Drain Leakage Current ( $V_{DS} = 28\text{ Vdc}$ , $V_{GS} = 0\text{ Vdc}$ )	$I_{DSS}$	—	—	1	$\mu\text{Adc}$
Gate-Source Leakage Current ( $V_{GS} = 5\text{ Vdc}$ , $V_{DS} = 0\text{ Vdc}$ )	$I_{GSS}$	—	—	1	$\mu\text{Adc}$

**On Characteristics (DC)**

Gate Threshold Voltage ( $V_{DS} = 10\text{ Vdc}$ , $I_D = 200\ \mu\text{Adc}$ )	$V_{GS(th)}$	1.5	2.2	2.5	Vdc
Gate Quiescent Voltage ( $V_{DS} = 28\text{ Vdc}$ , $I_D = 610\ \text{mAdc}$ )	$V_{GS(Q)}$	2	2.8	4	Vdc
Drain-Source On-Voltage ( $V_{GS} = 10\text{ Vdc}$ , $I_D = 2.0\ \text{Adc}$ )	$V_{DS(on)}$	—	0.3	—	Vdc

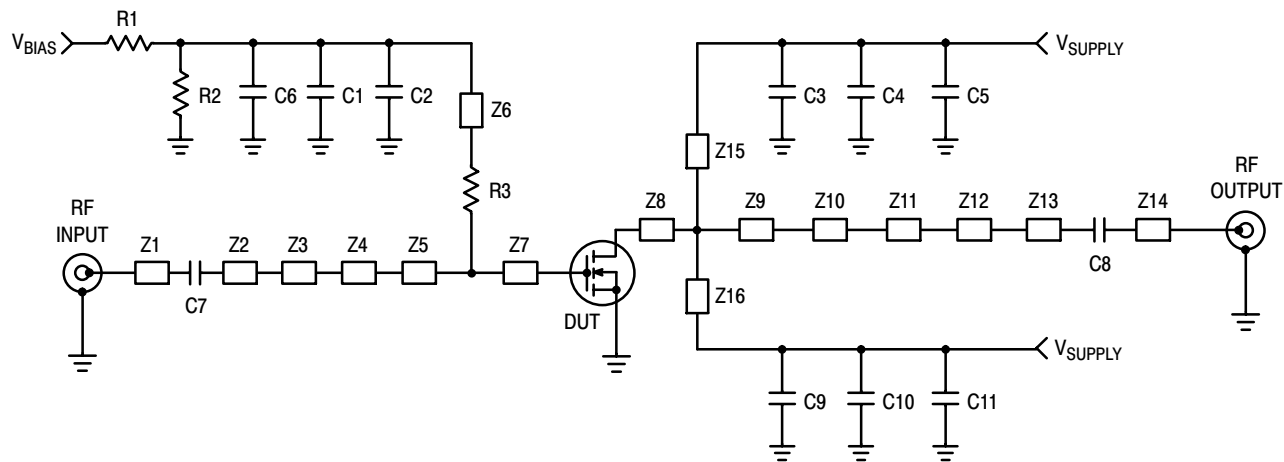
**Dynamic Characteristics <sup>(1)</sup>**

Reverse Transfer Capacitance ( $V_{DS} = 28\text{ Vdc} \pm 30\ \text{mV(rms)ac}$ @ 1 MHz, $V_{GS} = 0\text{ Vdc}$ )	$C_{rss}$	—	1.5	—	pF
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**Functional Tests** (In Freescale Test Fixture, 50 ohm system)  $V_{DD} = 28\text{ Vdc}$ ,  $I_{DQ} = 610\ \text{mA}$ ,  $P_{out} = 14\ \text{W Avg.}$ ,  $f_1 = 2112.5\ \text{MHz}$ ,  $f_2 = 2122.5\ \text{MHz}$  and  $f_1 = 2157.5\ \text{MHz}$ ,  $f_2 = 2167.5\ \text{MHz}$ , 2-carrier W-CDMA, 3.84 MHz Channel Bandwidth Carriers. ACPR measured in 3.84 MHz Channel Bandwidth @  $\pm 5\ \text{MHz}$  Offset. IM3 measured in 3.84 MHz Bandwidth @  $\pm 10\ \text{MHz}$  Offset. PAR = 8.5 dB @ 0.01% Probability on CCDF.

Power Gain	$G_{ps}$	13.5	15.5	16.5	dB
Drain Efficiency	$\eta_D$	24.5	26	—	%
Intermodulation Distortion	IM3	—	-37	-35	dBc
Adjacent Channel Power Ratio	ACPR	—	-40	-38	dBc
Input Return Loss	IRL	—	-14	-10	dB

1. Part is internally matched both on input and output.



Z1	0.250" x 0.080" Microstrip	Z10	0.270" x 0.300" Microstrip
Z2	0.860" x 0.080" Microstrip	Z11	0.230" x 0.080" Microstrip
Z3	0.300" x 0.405" Microstrip	Z12	0.310" x 0.300" Microstrip
Z4	0.350" x 0.080" Microstrip	Z13	0.830" x 0.080" Microstrip
Z5	0.350" x 0.755" Microstrip	Z14	0.200" x 0.080" Microstrip
Z6	0.680" x 0.080" Microstrip	Z15	1.000" x 0.080" Microstrip
Z7	0.115" x 0.755" Microstrip	Z16	1.100" x 0.070" Microstrip
Z8	0.115" x 1.000" Microstrip	PCB	Arlon AD250, 0.030", $\epsilon_r = 2.5$
Z9	0.240" x 1.000" Microstrip		

**Figure 1. MRF6S21060NR1(NBR1) Test Circuit Schematic**

**Table 6. MRF6S21060NR1(NBR1) Test Circuit Component Designations and Values**

Part	Description	Part Number	Manufacturer
C1	100 nF Chip Capacitor	CDR33BX104AKYS	Kemet
C2, C7	4.7 pF Chip Capacitors	ATC100B4R7BT500XT	ATC
C3, C8, C9	6.8 pF Chip Capacitors	ATC100B6R8BT500XT	ATC
C4, C5, C6, C10, C11	10 $\mu$ F, 35 V Chip Capacitors	GRM55DR61H106KA88L	Murata
R1	1 k $\Omega$ , 1/4 W Chip Resistor	CRCW12061000FKTA	Vishay
R2	10 k $\Omega$ , 1/4 W Chip Resistor	CRCW12061001FKTA	Vishay
R3	10 $\Omega$ , 1/4 W Chip Resistor	CRCW120610R0FKTA	Vishay

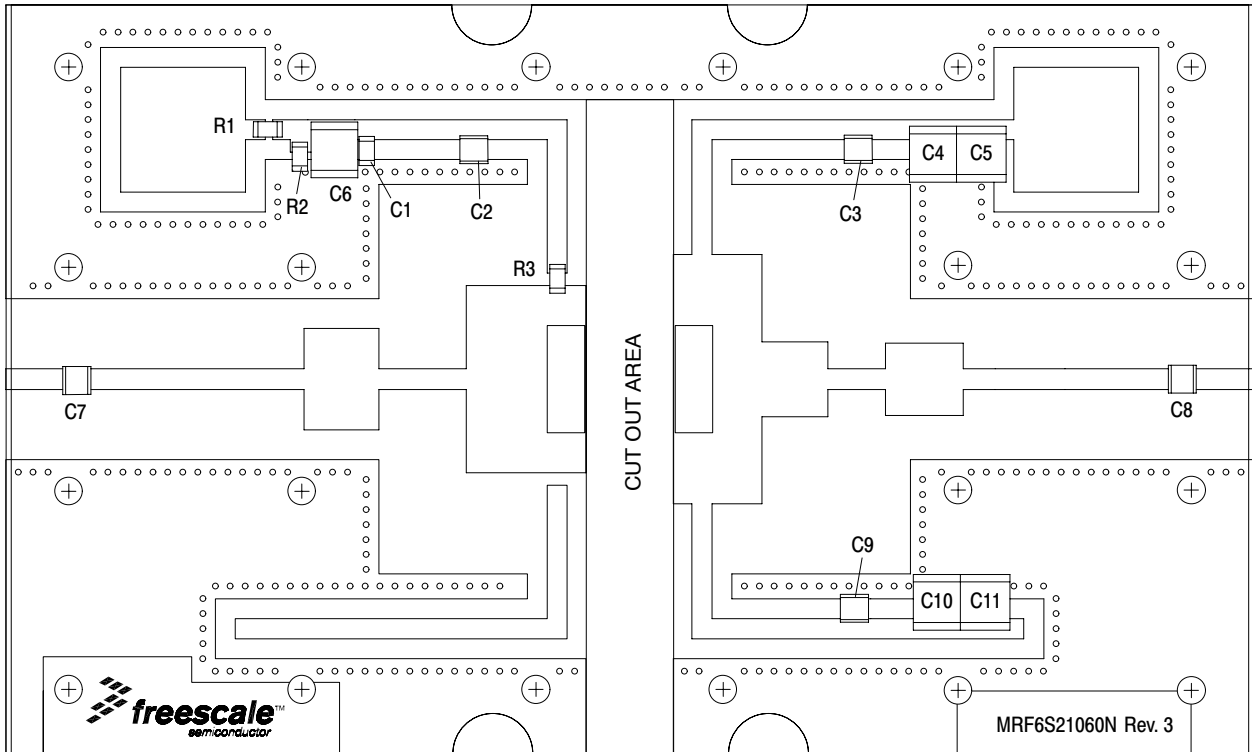


Figure 2. MRF6S21060NR1(NBR1) Test Circuit Component Layout

## TYPICAL CHARACTERISTICS

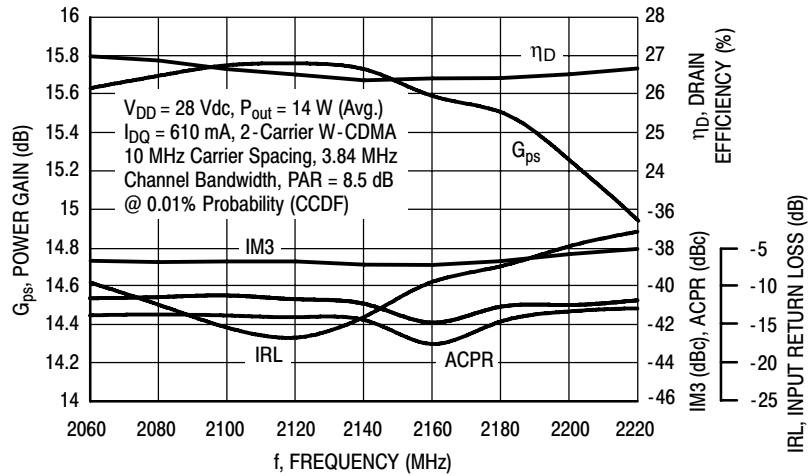


Figure 3. 2-Carrier W-CDMA Broadband Performance @  $P_{out} = 14$  Watts Avg.

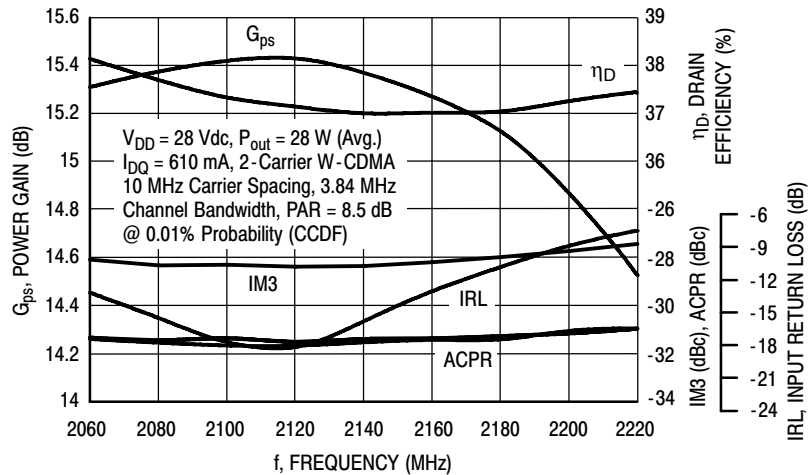


Figure 4. 2-Carrier W-CDMA Broadband Performance @  $P_{out} = 28$  Watts Avg.

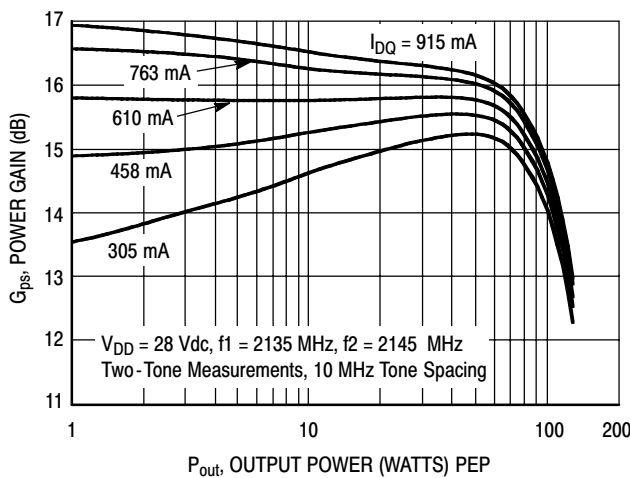


Figure 5. Two-Tone Power Gain versus Output Power

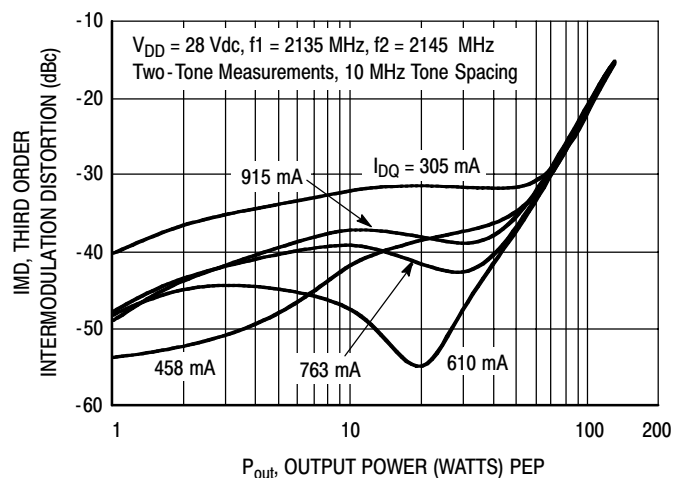
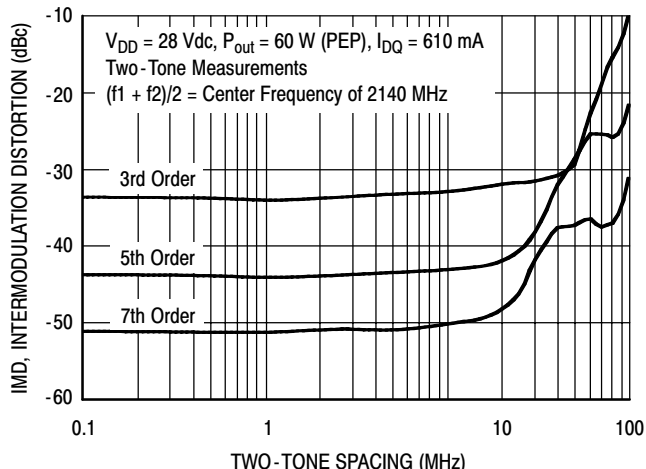
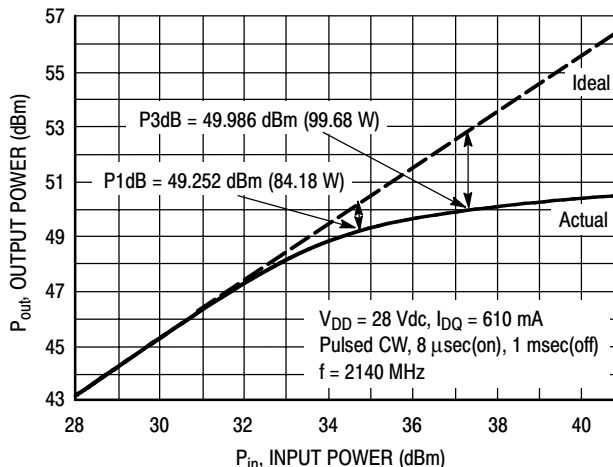


Figure 6. Third Order Intermodulation Distortion versus Output Power

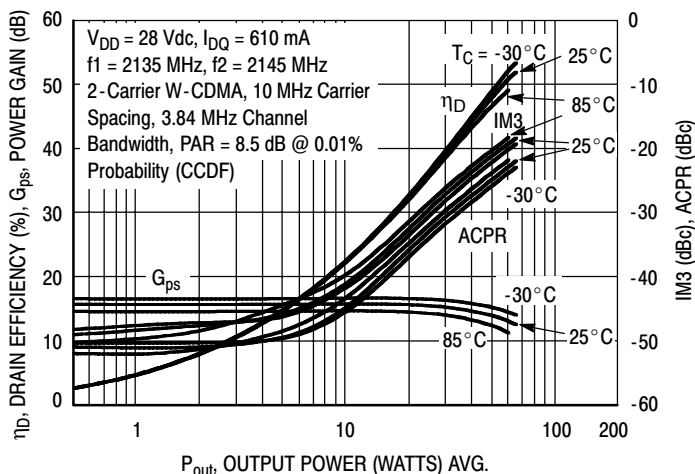
## TYPICAL CHARACTERISTICS



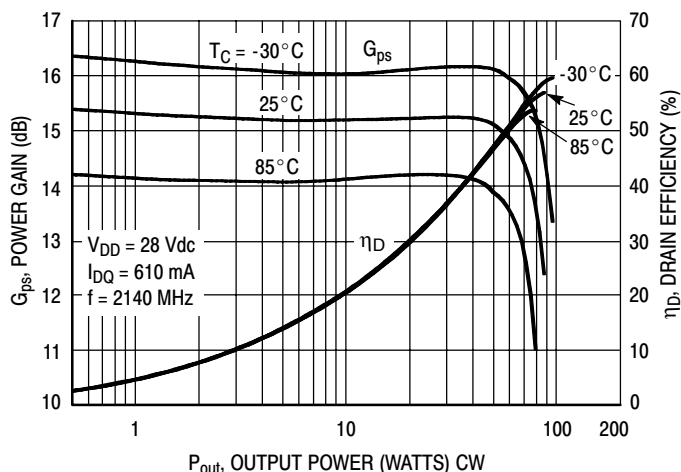
**Figure 7. Intermodulation Distortion Products versus Tone Spacing**



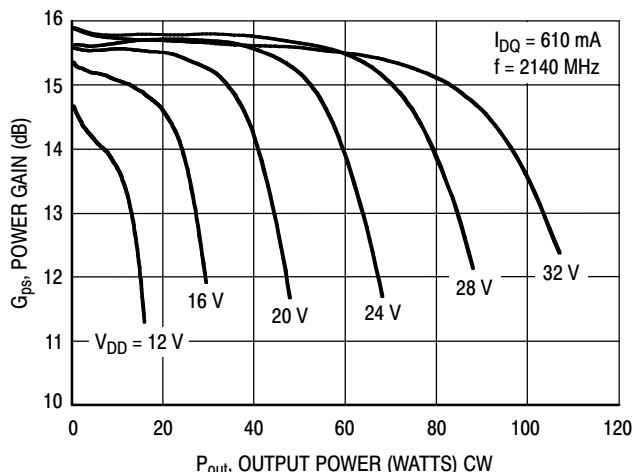
**Figure 8. Pulse CW Output Power versus Input Power**



**Figure 9. 2-Carrier W-CDMA ACPR, IM3, Power Gain and Drain Efficiency versus Output Power**

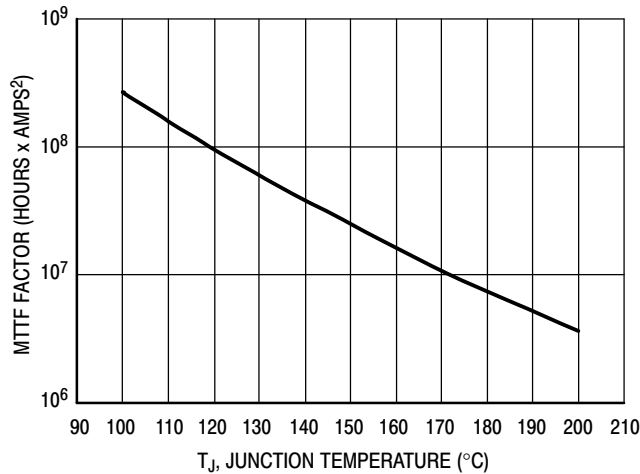


**Figure 10. Power Gain and Drain Efficiency versus CW Output Power**



**Figure 11. Power Gain versus Output Power**

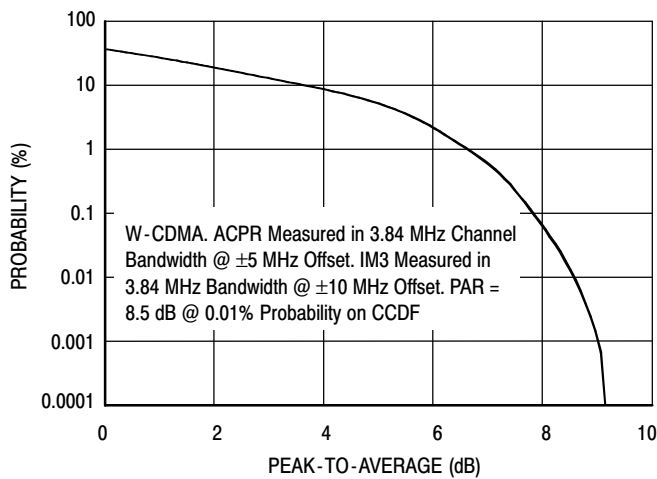
## TYPICAL CHARACTERISTICS



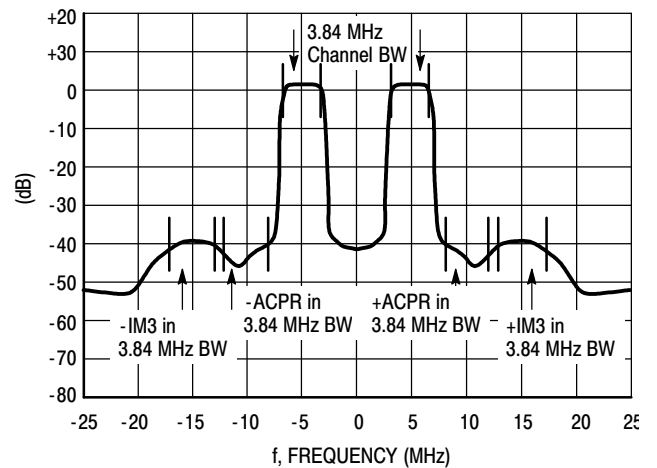
This above graph displays calculated MTTF in hours x ampere<sup>2</sup> drain current. Life tests at elevated temperatures have correlated to better than  $\pm 10\%$  of the theoretical prediction for metal failure. Divide MTTF factor by  $I_D^2$  for MTTF in a particular application.

**Figure 12. MTTF Factor versus Junction Temperature**

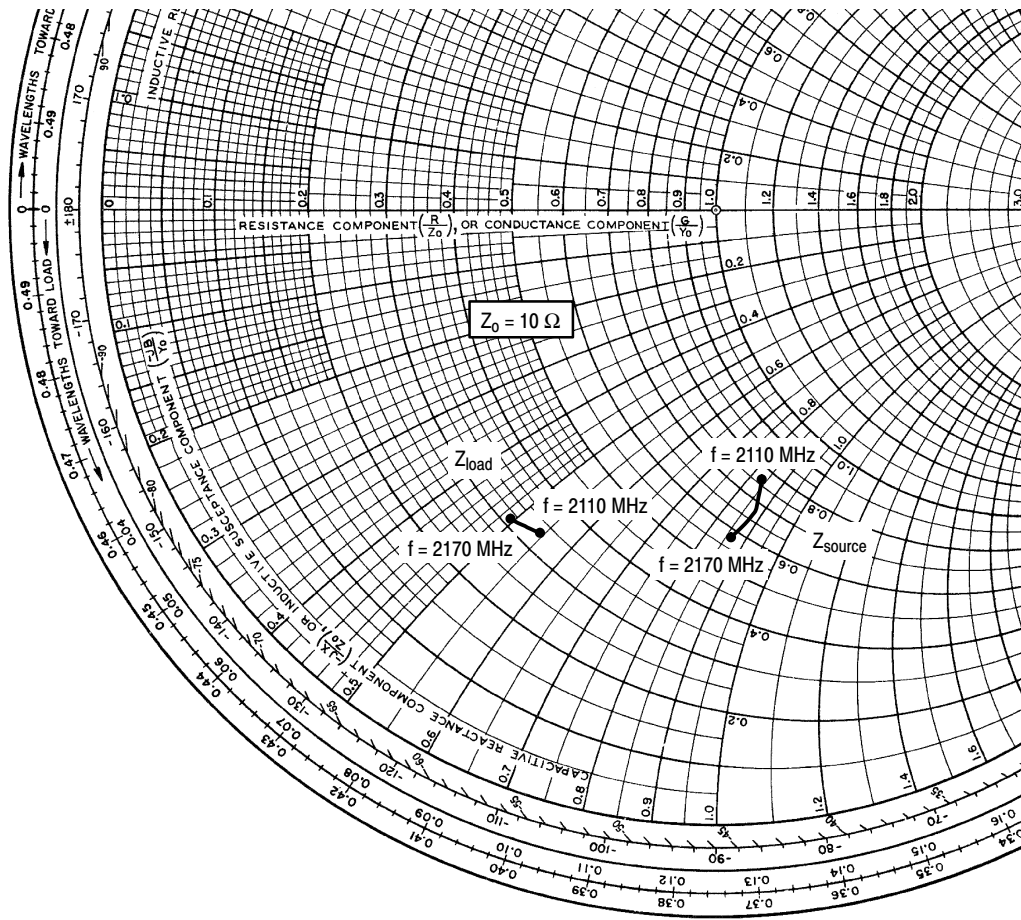
## W-CDMA TEST SIGNAL



**Figure 13. CCDF W-CDMA 3GPP, Test Model 1, 64 DPCH, 67% Clipping, Single-Carrier Test Signal**



**Figure 14. 2-Carrier W-CDMA Spectrum**



$V_{DD} = 28 \text{ Vdc}$ ,  $I_{DQ} = 610 \text{ mA}$ ,  $P_{out} = 14 \text{ W Avg.}$

f MHz	$Z_{source}$ $\Omega$	$Z_{load}$ $\Omega$
2110	$7.59 - j8.39$	$3.31 - j5.35$
2140	$6.71 - j8.83$	$3.17 - j5.16$
2170	$5.84 - j8.62$	$3.06 - j4.92$

$Z_{source}$  = Test circuit impedance as measured from gate to ground.

$Z_{load}$  = Test circuit impedance as measured from drain to ground.

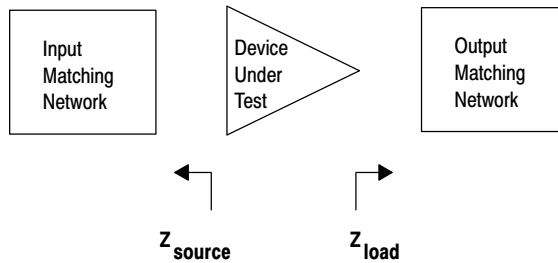
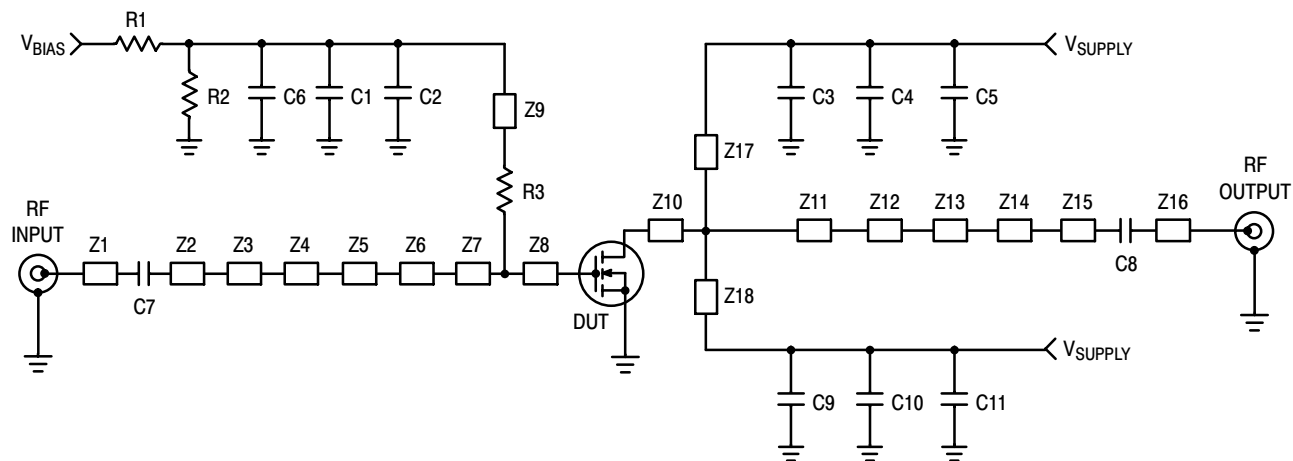


Figure 15. Series Equivalent Source and Load Impedance



## TD-SCDMA CHARACTERIZATION



Z1	0.250" x 0.080" Microstrip	Z11	0.240" x 1.000" Microstrip
Z2	0.129" x 0.080" Microstrip	Z12*	0.270" x 0.360" Microstrip
Z3*	0.565" x 0.258" Microstrip	Z13	0.230" x 0.080" Microstrip
Z4	0.160" x 0.080" Microstrip	Z14*	0.588" x 0.290" Microstrip
Z5*	0.300" x 0.455" Microstrip	Z15	0.595" x 0.080" Microstrip
Z6	0.350" x 0.080" Microstrip	Z16	0.200" x 0.080" Microstrip
Z7	0.350" x 0.755" Microstrip	Z17	0.935" x 0.080" Microstrip
Z8	0.115" x 0.755" Microstrip	Z18	0.955" x 0.080" Microstrip
Z9	0.680" x 0.080" Microstrip	PCB	Arlon AD250, 0.030", $\epsilon_r = 2.5$
Z10	0.115" x 1.000" Microstrip		* Copper foil tape soldered onto PCB

**Figure 16. MRF6S21060NR1(NBR1) Test Circuit Schematic — TD-SCDMA**

**Table 7. MRF6S21060NR1(NBR1) Test Circuit Component Designations and Values — TD-SCDMA**

Part	Description	Part Number	Manufacturer
C1	100 nF Chip Capacitor	CDR33BX104AKYS	Kemet
C2, C7	4.7 pF Chip Capacitors	ATC100B4R7BT500XT	ATC
C3, C8, C9	6.8 pF Chip Capacitors	ATC100B6R8BT500XT	ATC
C4, C5, C6, C10, C11	10 $\mu$ F, 35 V Chip Capacitors	GRM55DR61H106KA88L	Murata
R1	1 k $\Omega$ , 1/4 W Chip Resistor	CRCW12061000FKTA	Vishay
R2	10 k $\Omega$ , 1/4 W Chip Resistor	CRCW12061001FKTA	Vishay
R3	10 $\Omega$ , 1/4 W Chip Resistor	CRCW120610R0FKTA	Vishay

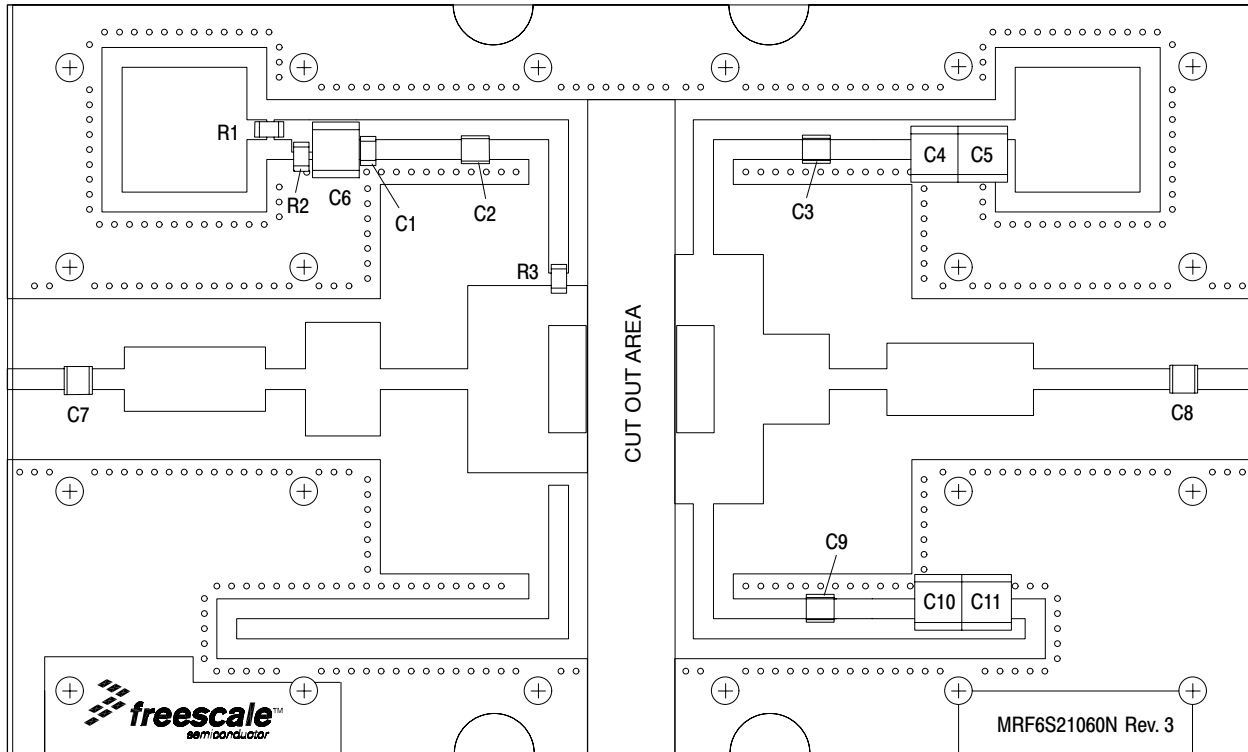
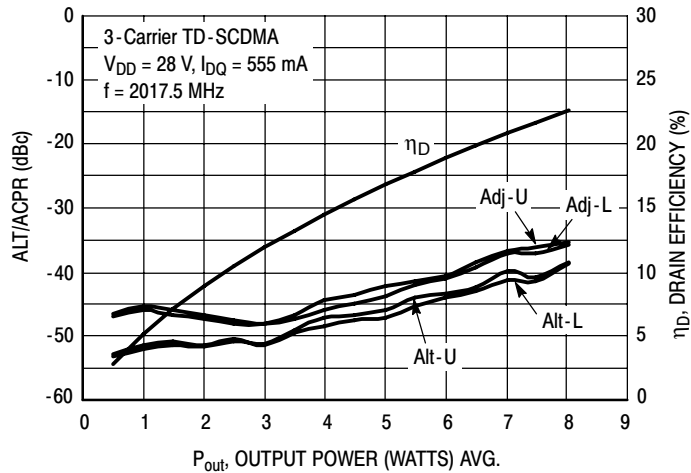
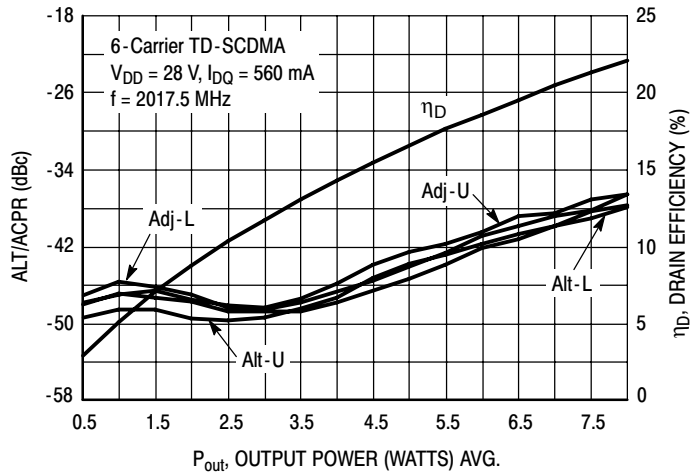


Figure 17. MRF6S21060NR1(NBR1) Test Circuit Component Layout — TD-SCDMA

## TYPICAL CHARACTERISTICS

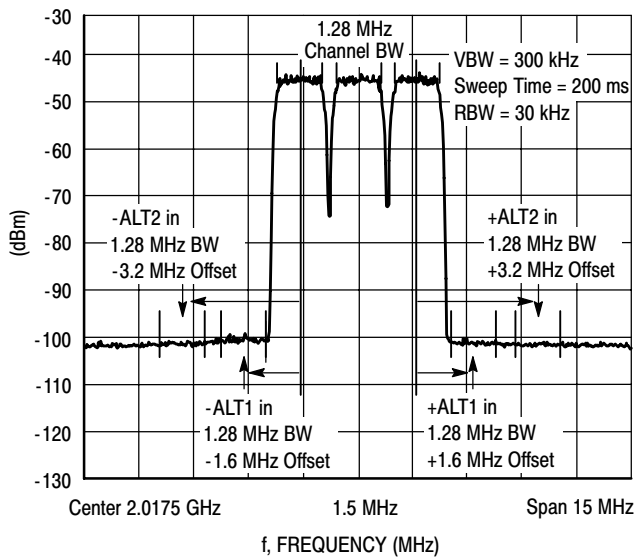


**Figure 18. 3-Carrier TD-SCDMA ACPR, ALT and Drain Efficiency versus Output Power**

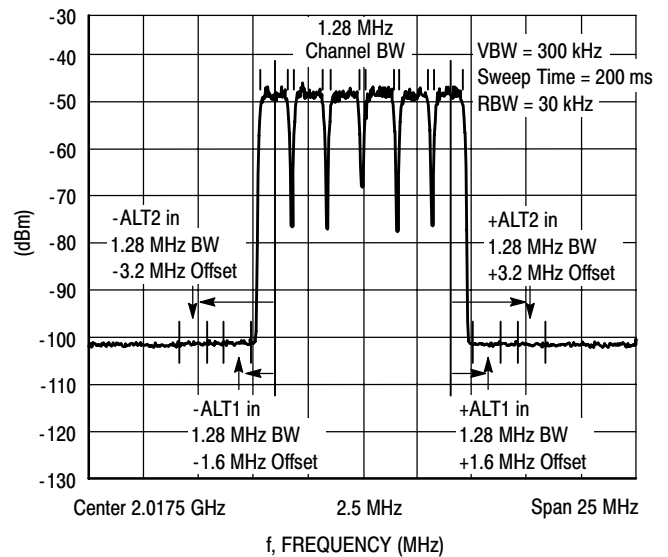


**Figure 19. 6-Carrier TD-SCDMA ACPR, ALT and Drain Efficiency versus Output Power**

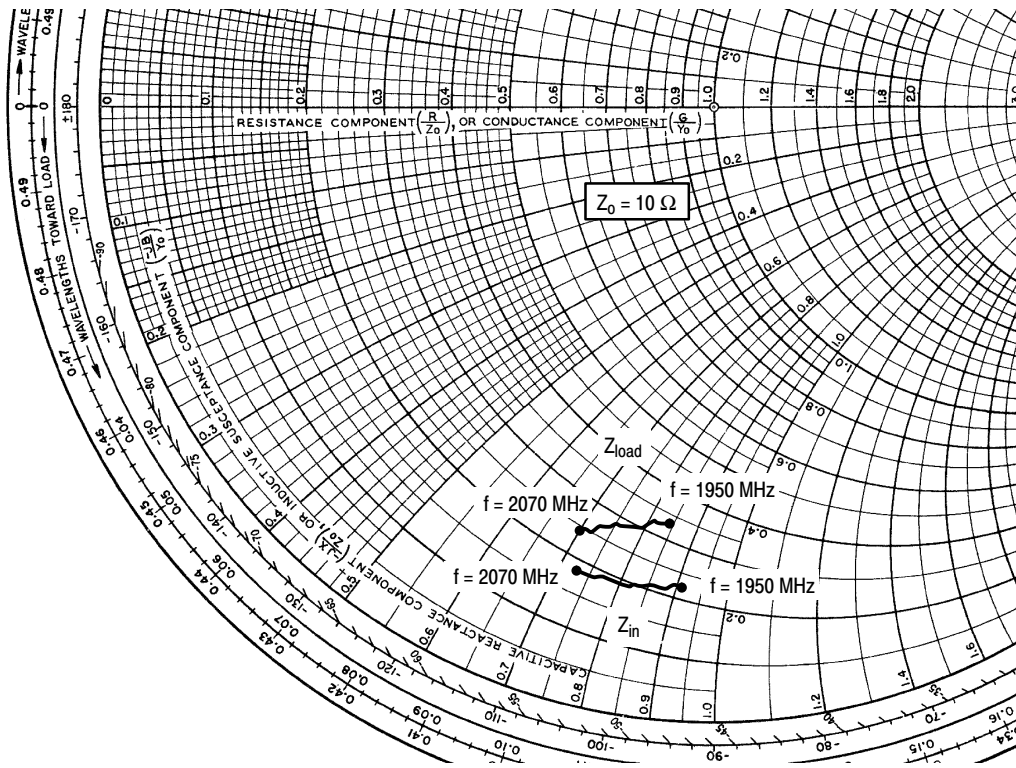
## TD-SCDMA TEST SIGNAL



**Figure 20. 3-Carrier TD-SCDMA Spectrum**



**Figure 21. 6-Carrier TD-SCDMA Spectrum**



$V_{DD} = 28 \text{ Vdc}$ ,  $I_{DQ} = 560 \text{ mA}$

f MHz	$Z_{in}$ $\Omega$	$Z_{load}$ $\Omega$
1950	2.227 - j9.127	3.341 - j8.372
1960	2.168 - j8.942	3.239 - j8.218
1970	2.124 - j8.757	3.168 - j8.084
1980	2.073 - j8.606	3.083 - j7.966
1990	2.031 - j8.447	3.009 - j7.865
2000	1.987 - j8.306	2.929 - j7.743
2010	1.940 - j8.155	2.845 - j7.639
2020	1.911 - j8.000	2.775 - j7.529
2030	1.891 - j7.835	2.696 - j7.410
2040	1.856 - j7.711	2.615 - j7.309
2050	1.831 - j7.589	2.549 - j7.207
2060	1.808 - j7.461	2.479 - j7.086
2070	1.782 - j7.325	2.422 - j6.983

$Z_{in}$  = Device input impedance as measured from gate to ground.

$Z_{load}$  = Test circuit impedance as measured from drain to ground.

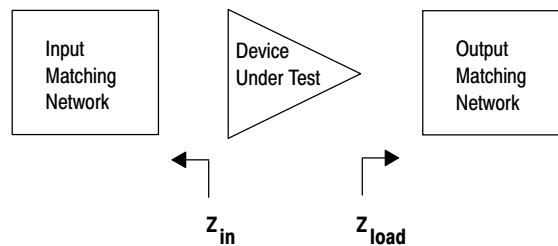
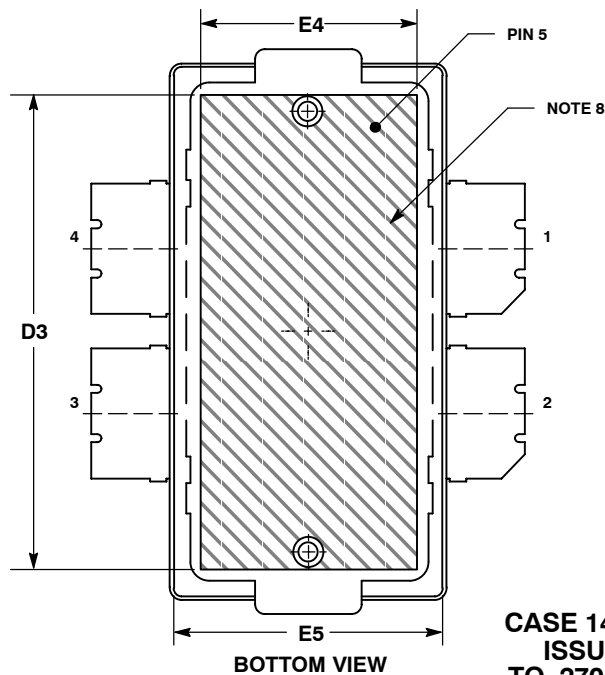
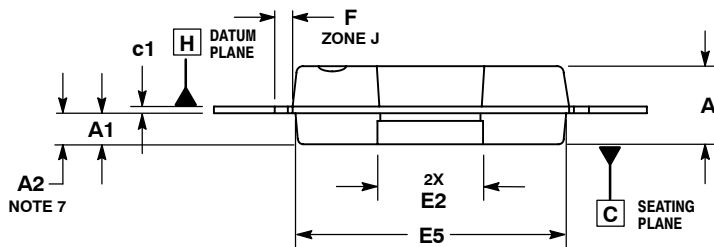
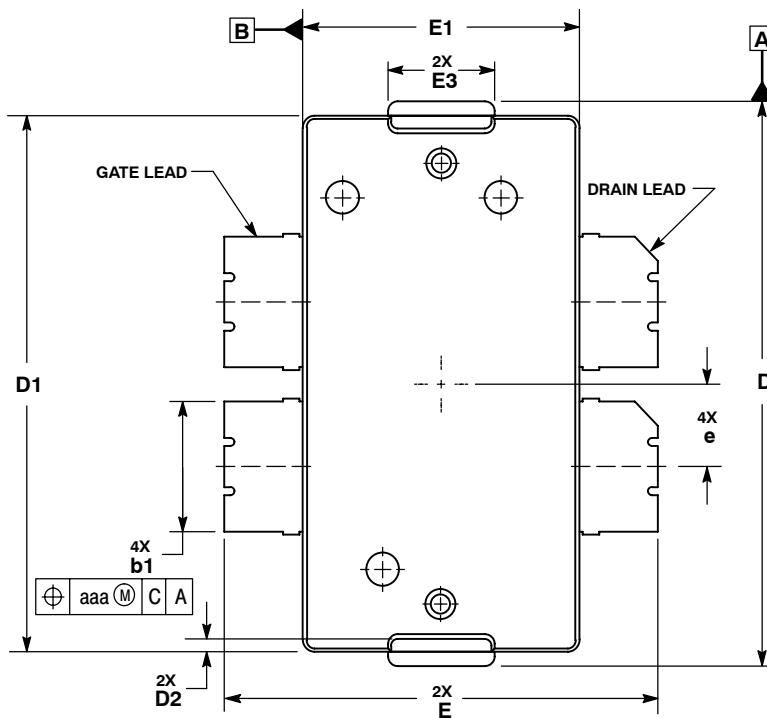


Figure 22. Series Equivalent Input and Load Impedance — TD-SCDMA

# PACKAGE DIMENSIONS



**CASE 1486-03  
ISSUE C  
TO-270 WB-4  
PLASTIC  
MRF6S21060NR1**

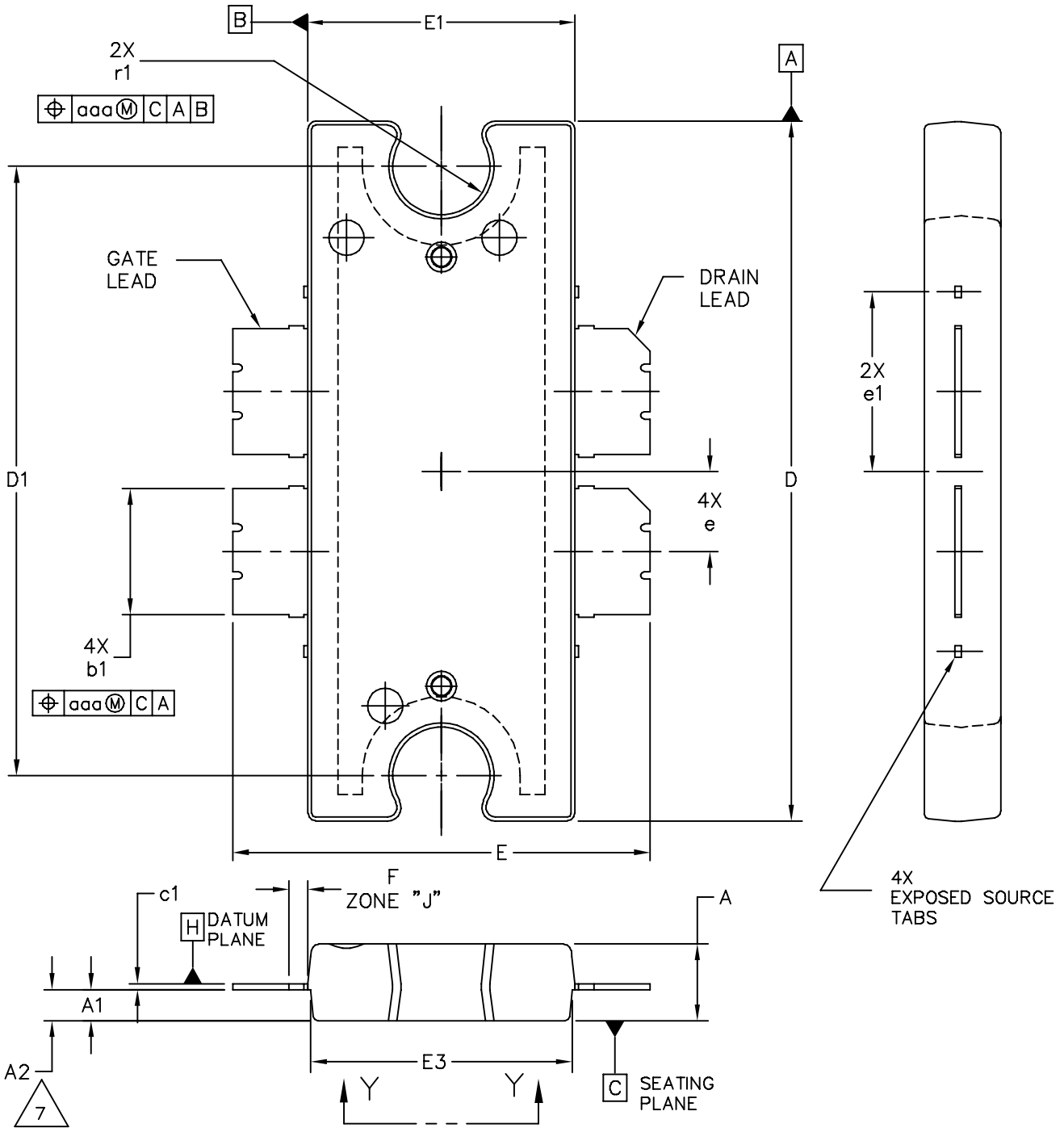
**NOTES:**

1. CONTROLLING DIMENSION: INCH.
2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M-1994.
3. DATUM PLANE -H- IS LOCATED AT THE TOP OF LEAD AND IS COINCIDENT WITH THE LEAD WHERE THE LEAD EXITS THE PLASTIC BODY AT THE TOP OF THE PARTING LINE.
4. DIMENSIONS "D" AND "E1" DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS .006 PER SIDE. DIMENSIONS "D" AND "E1" DO INCLUDE MOLD MISMATCH AND ARE DETERMINED AT DATUM PLANE -H-.
5. DIMENSION "b1" DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE .005 TOTAL IN EXCESS OF THE "b1" DIMENSION AT MAXIMUM MATERIAL CONDITION.
6. DATUMS -A- AND -B- TO BE DETERMINED AT DATUM PLANE -H-.
7. DIMENSION A2 APPLIES WITHIN ZONE "J" ONLY.
8. HATCHING REPRESENTS THE EXPOSED AREA OF THE HEAT SLUG.

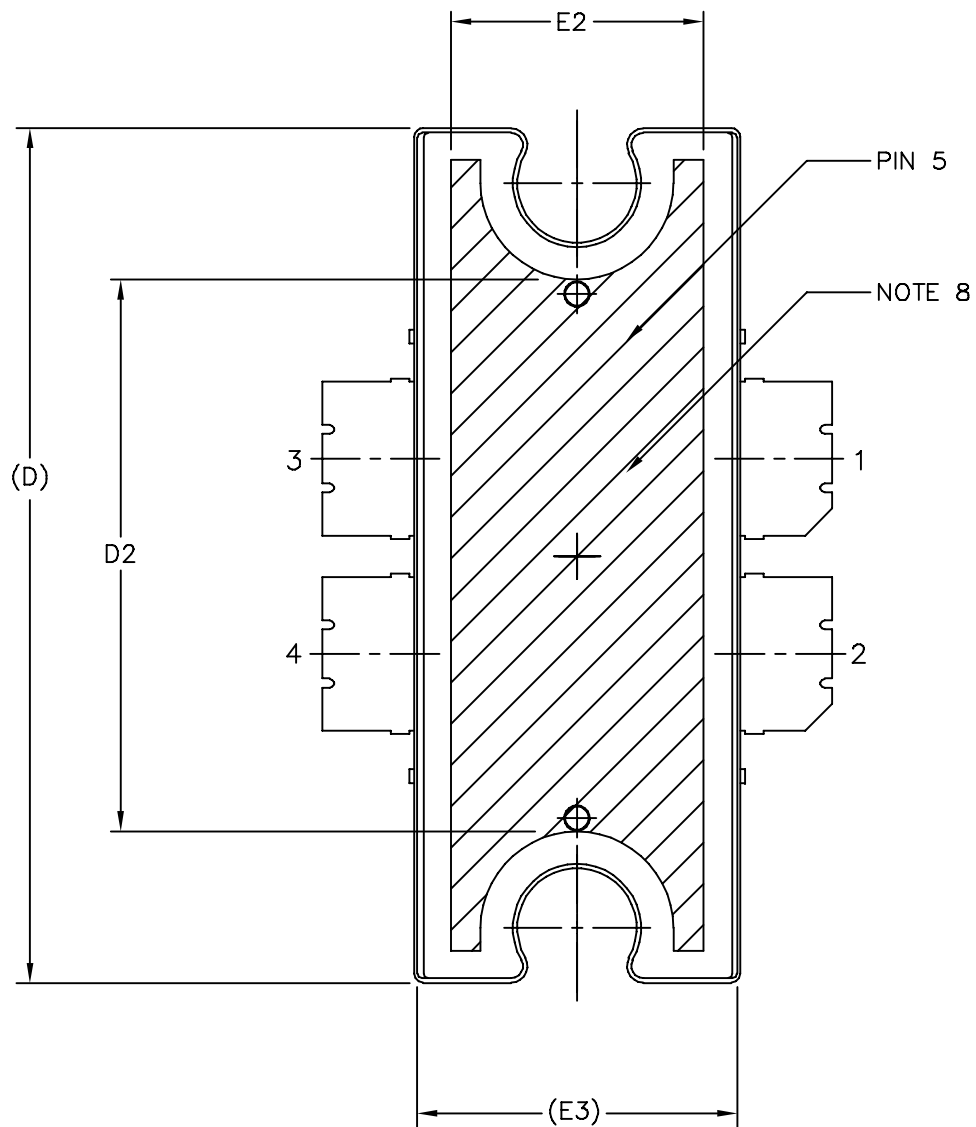
DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.100	.104	2.54	2.64
A1	.039	.043	0.99	1.09
A2	.040	.042	1.02	1.07
D	.712	.720	18.08	18.29
D1	.688	.692	17.48	17.58
D2	.011	.019	0.28	0.48
D3	.600	---	15.24	---
E	.551	.559	14	14.2
E1	.353	.357	8.97	9.07
E2	.132	.140	3.35	3.56
E3	.124	.132	3.15	3.35
E4	.270	---	6.86	---
E5	.346	.350	8.79	8.89
F	.025 BSC		0.64 BSC	
b1	.164	.170	4.17	4.32
c1	.007	.011	0.18	0.28
e	.106 BSC		2.69 BSC	
aaa	.004		0.10	

**STYLE 1:**

- PIN 1. DRAIN
- DRAIN
- GATE
- GATE
- SOURCE



© FREESCALE SEMICONDUCTOR, INC. ALL RIGHTS RESERVED.		<b>MECHANICAL OUTLINE</b>		PRINT VERSION NOT TO SCALE	
TITLE: TO-272 4 LEAD, WIDE BODY		DOCUMENT NO: 98ASA10575D		REV: D	
		CASE NUMBER: 1484-04		05 APR 2006	
		STANDARD: NON-JEDEC			



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TITLE: TO-272 4 LEAD, WIDE BODY	DOCUMENT NO: 98ASA10575D	REV: D	
	CASE NUMBER: 1484-04	05 APR 2006	
	STANDARD: NON-JEDEC		

MRF6S21060NR1 MRF6S21060NBR1

NOTES:

1. CONTROLLING DIMENSION: INCH
2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M-1994.
3. DATUM PLANE H IS LOCATED AT THE TOP OF LEAD AND IS COINCIDENT WITH THE LEAD WHERE THE LEAD EXITS THE PLASTIC BODY AT THE TOP OF THE PARTING LINE.
4. DIMENSIONS "D" AND "E1" DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS .006 PER SIDE. DIMENSIONS "D" AND "E1" DO INCLUDE MOLD MISMATCH AND ARE DETERMINED AT DATUM PLANE H.
5. DIMENSIONS "b1" DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE .005 TOTAL IN EXCESS OF THE "b1" DIMENSION AT MAXIMUM MATERIAL CONDITION.
6. DATUM A AND B TO BE DETERMINED AT DATUM PLANE H.
7. DIMENSION A2 APPLIES WITHIN ZONE "J" ONLY.
8. HATCHING REPRESENTS EXPOSED AREA OF THE HEAT SLUG. HATCHED AREA SHOWN IS ON THE SAME PLANE.

STYLE 1:  
 PIN 1 - DRAIN      PIN 2 - DRAIN  
 PIN 3 - GATE        PIN 4 - GATE  
 PIN 5 - SOURCE

DIM	INCH		MILLIMETER		DIM	INCH		MILLIMETER	
	MIN	MAX	MIN	MAX		MIN	MAX	MIN	MAX
A	.100	.104	2.54	2.64	b1	.164	.170	4.17	4.32
A1	.039	.043	0.99	1.09	c1	.007	.011	.18	.28
A2	.040	.042	1.02	1.07	r1	.063	.068	1.60	1.73
D	.928	.932	23.57	23.67	e	.106 BSC		2.69 BSC	
D1	.810 BSC		20.57 BSC		e1	.239 INFO ONLY		6.07 INFO ONLY	
D2	.600	---	15.24	---	aaa	.004		.10	
E	.551	.559	14	14.2					
E1	.353	.357	8.97	9.07					
E2	.270	---	6.86	---					
E3	.346	.350	8.79	8.89					
F	.025 BSC		0.64 BSC						

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TITLE:  TO-272 4 LEAD WIDE BODY		DOCUMENT NO: 98ASA10575D		REV: D	
		CASE NUMBER: 1484-04		05 APR 2006	
		STANDARD: NON-JEDEC			



## PRODUCT DOCUMENTATION

Refer to the following documents to aid your design process.

### Application Notes

- AN1955: Thermal Measurement Methodology of RF Power Amplifiers

### Engineering Bulletins

- EB212: Using Data Sheet Impedances for RF LDMOS Devices

## REVISION HISTORY

The following table summarizes revisions to this document.

Revision	Date	Description
4	Dec. 2006	<ul style="list-style-type: none"><li>• Added "TD-SCDMA" to data sheet description, p. 1</li><li>• Updated Part Numbers in Table 6, Component Designations and Values, to RoHS compliant part numbers, p. 3</li><li>• Added TD-SCDMA test circuit schematic, component designations and values, component layout, typical characteristic curves, test signal and series impedance, p. 9-12</li><li>• Added Product Documentation and Revision History, p. 17</li></ul>

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